

Annealing Effects and Film Thickness Dependence of Cobalt Selenide Thin Films Grown By the Chemical Bath Deposition Method

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Abstract : *Thin films of CoSe (cobalt selenide) were prepared using the chemical bath deposition technique. The deposition variables such as the pH, bath temperature, and source to substrate distance were kept constant and the film thickness was varied by varying the concentrations. The films were then annealed at annealing temperatures ≤ 250 °C. The films were characterised using scanning electron microscopy (SEM), energy dispersive x-ray spectroscopy (EDAX), and X-ray Diffractometry (XRD) to investigate the morphological, compositional and structural properties of the as-deposited and annealed layers. The results show that the post-deposition annealing improved the properties of the layers. In particular, an increase in the grain size was recorded for annealing temperatures ≤ 200 °C.*

Keywords:– *Annealing, Chemical bath deposition, Film thickness, Grain size, Thin films*

I. Introduction

The use of different selenides in thin film form for applications in different electronic, optoelectronics and in nanotechnology industry has been widely reported in the literature. In recent times, interest in the chalcogenides of semiconductors, metals and transition metals have increased tremendously because of their tunable properties which makes them useful candidates in various electronics and optoelectronic devices including solar cells, sensor, laser materials, photoconductors, diodes and transistors [1-15]. It is generally understood that chemical techniques for the preparation of semiconducting chalcogenides thin films offer the advantages of economy, convenience and the capability of large-area deposition. Thin film deposition of chalcogenides of nickel, bismuth, antimony, cadmium, copper, zinc tin, and indium selenides have been reported by various research groups [16-25]. Most recently, cobalt selenides is reported to be used as high performance counter electrodes in dye sensitized solar cells [26-27], as catalysts [28], waste water treatments [29], photoelectrodes [30-32], and magnetic devices [33].

It has been established in the literature by different research groups that thin films of cobalt selenides can be grown using different low cost deposition techniques. These deposition methods include chemical bath deposition technique [34-35], electro-deposition [30-32, 36-38], solvothermal synthesis [29], and chemical synthesis [39-41]. Chemical bath deposition is a cost effective technique that yield high quality thin films and the basic principles is mostly by the controlled precipitation of the desired compound from a solution of its constituents. In the present investigation, the deposition of cobalt selenides thin films grown by chemical bath deposition at room temperature is reported, with emphasis on the influence of the different annealing temperatures on the morphological compositional and structural properties of the films. The effect of the deposition conditions and post deposition annealing on the film thickness is also presented. This report is a fundamental step in determining the optimised conditions needed for increased efficiency of cobalt selenides thin films especially when utilised in electronic devices such as solar cells, diodes, and transistors.

II. Materials And Method

The glass microslides used as substrates were initially soaked in dilute hydrochloric acid for 2 hours, removed and dipped into acetone for 1 hour after which they were removed, washed with foam- sponge in ethanol and finally rinsed in distilled water. They were then dried in oven at 30°C above room temperature for 30 minutes. Before deposition of films on them, the substrates were brought out of the oven and their temperature allowed to drop to room temperature. Pre-cleaned glass substrates were then inserted vertically into the growth mixtures using synthetic foam. The loaded substrates were labelled for easy identification. The deposition time was fixed for 4 h at a constant temperature of 60 °C. The films were removed and rinsed with distilled water and then dried in air. The films were then annealed in an oven with the annealing temperatures kept between the range of 100 °C to 250 °C with the annealing time fixed for 1 hour.

The films were characterised using scanning electron microscopy to investigate the morphological properties, using the Hitachi 5-4200 analytical scanning electron Microscope at Sheda Science and Technology complex, Abuja, Nigeria. The compositional analysis was done with the energy dispersive X-ray spectroscopy. The photomicrographs of the thin films were taken with Olympus B.H.3 photomicroscope at 200 magnification at Engineering and Material Development Institute, Akure, Nigeria. The structural characterisation was done with the X-ray diffractometry with the MD -10 mini diffractometer at Engineering and Material Development Institute, Akure, Nigeria.

III. Results And Discussion

Fig. 1 show the scanning electron micrograph for a typical as-deposited CoSe thin film for a thickness of 550 nm. As indicated in Fig. 1, the grains are relatively scattered with dense leaf-like structures. This scattering of grains can be due to the mode of the film formation. Film formation for chemical bath deposited films is mostly by nucleation. The major modes of film formation has been widely discussed in the literature [42]. In the literature, variation of grain morphology have been reported for other chalcogenides thin films independent of the deposition techniques [1, 13, 21] while Guar et al [39] reported on poly-crystalline leaf-like cobalt selenide thin films.

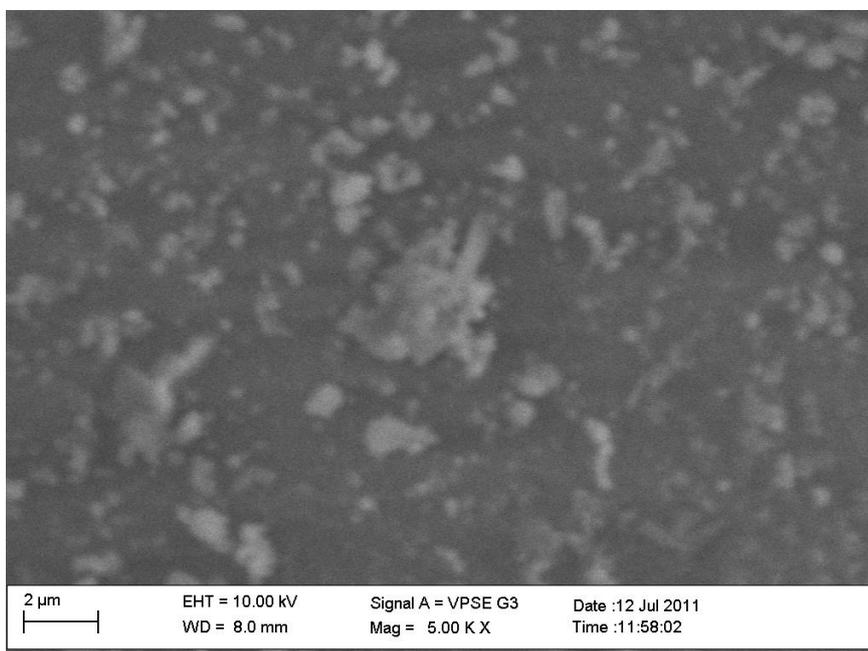


Fig. 1. Scanning electron micrograph of CoSe thin film with film thickness of 550 nm

Fig. 2 gives the scanning electron micrograph of an annealed CoSe thin film. As shown in Fig. 2, there was a clear evidence of the densification of the grains after the post-deposition heat treatments. The grains were enlarged such that the islands that were slightly observed physically in Fig. 1, were almost filled up, implying a decrease in the grain boundary. Post-deposition annealing is amongst the established process of improving grain size in thin film deposition. An increase in the grain size due to post-deposition annealing has been reported by other authors independent of the deposition techniques [43-44].

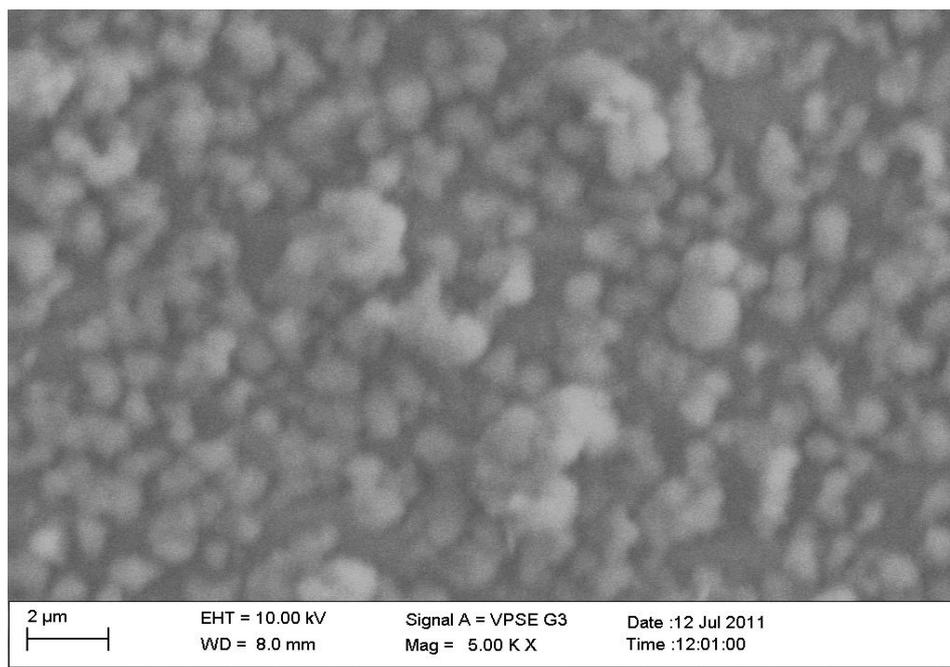


Fig. 2. Scanning electron micrograph of annealed CoSe thin film with film thickness of 545 nm

From the X-ray diffraction (XRD) profiles of the CoSe thin films deposited using different film thicknesses, the spectra (not shown) indicated that all the grown films were polycrystalline in nature. The films had the hexagonal crystal structure with observed peaks that are consistent with the Powder Diffraction File: 25-0125. The observed prominent peaks included the <121>, <112>, <222>, <212>, and <032> diffraction peaks that correspond to CoSe, in line with the Joint Committee on Powder Diffraction Standard (JCPDS) : 25-0125. Wang et al [38] reported on electrodeposited Se-rich CoSe thin films and observed similar hexagonal crystal structure and compact morphology, while Lai et al [30] also observed hexagonal crystal structure for electrodeposited CoSe thin films. The data extracted from the X-ray diffractometry analysis was used to deduce the crystallite size using the Scherrer’s formula. The Scherrer’s formula is given in the literature as [21-23, 42-43];

$$D = \frac{0.94 \lambda}{\beta \cos \theta} \tag{1}$$

In equation (1), D is the crystallite size, β is the full width at half maximum (FWHM) of the diffraction peak, θ is the Bragg angle, and λ is the wavelength of CuK α radiation source given as ($\lambda = 0.15406$ nm). The results show that the best layers had an average crystallite size of 30.61 nm. This is indicated in Table 1.

Table 1: Variation of crystallite size of annealed CoSe Thin Films (film thickness = 545 nm)

2 θ	<h k l>	d	FWHM	Crystallite Size (nm)
28.71	1 2 1	3.109	0.276	53.85
30.19	1 1 2	2.960	1.329	11.28
39.49	2 2 2	2.261	0.812	18.82
40.90	2 1 2	2.206	0.226	68.34
41.17	0 3 2	2.192	0.208	7.73

Fig. 3 indicates the variation of film thickness with concentration. As shown on Fig. 3, the film thickness was maximum at the concentration of 0.25 M, and then decreased thereafter. The decrease in film thickness for concentrations > 0.25 M was attributed to the effect of dissociation in the growth media. Other research groups have reported similar findings in the literature [45].

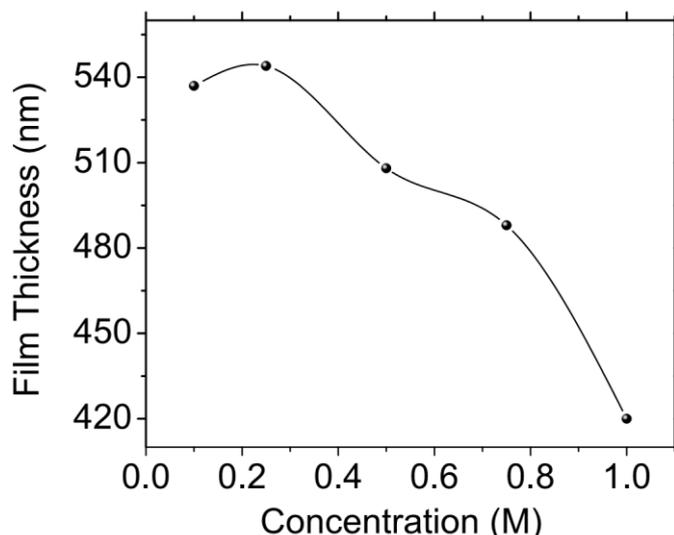


Fig. 3. Variation of film thickness at different concentrations.

Fig. 4 show the effect of the post-deposition annealing on the film thickness of the cobalt selenides thin films at the different annealing temperatures. As shown on Fig. 4, there is an increase in the film thickness for annealing temperatures ≤ 200 °C. The observed increase in the film thickness is

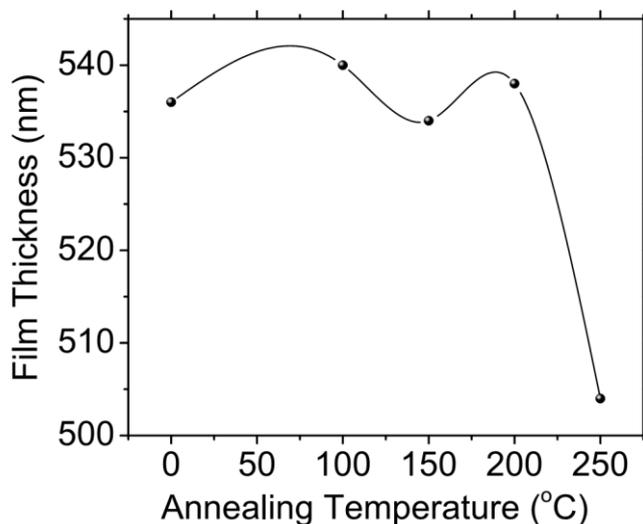


Fig. 4. Variation of film thickness at different annealing temperatures.

In line with the earlier observation indicated in Fig. 2. The increase in the film thickness was due to the increase in the grain sizes induced by the post- deposition heat treatments. Increase in film thickness caused by the change of deposition variables/post deposition annealing has been widely reported in the literature [46-47]. Cifuentes et al [48], observed an increase of film thickness for thermally evaporated SnS thin films and noted that this was caused by the changes in the band structure and the superposition degree of electron clouds of neighboring atoms in the films.

IV. Conclusion

In the present investigation, the morphological, compositional and structural properties of cobalt selenides thin films grown using the chemical bath deposition method, and the effect of post-deposition annealing on the as-grown layers is reported. The results show that the influence of annealing on the layers resulted on the increase in the crystallite size with better and uniform film thicknesses. The average crystallite size that was obtained for the best layers was 30.61 nm.

Acknowledgements

The authors are grateful to the staff of the Engineering and Material Development Institute, Akure, Nigeria, and Sheda Science and Technology Complex, Abuja, Nigeria for the characterisation of the films.

References

- [1] K.S. Kumar, C. Manoharan, S. Dhanapandian, A Gowri Manohari, Effect of Sb dopant on the structural, optical and electrical properties of SnS thin films by spray pyrolysis technique, *Spectrochimica Acta Part A: Molecular and Biomolecular Spectroscopy*, 115, 2013, 840-844.
- [2] P.E. Agbo, F.U. Nweke, P.A. Nwofe, C.N. Ukwu, Effects of concentration on the properties of Zn-doped Cadmium Sulphide thin films, *International Journal of Science and Research*, 3(11), 2014, 1832 – 1837.
- [3] S. Massaccesi, S. Sanchez, J. Vedel, Cathodic deposition of copper selenide films on tin oxide in sulfate solutions. *Journal of The Electrochemical Society*, 140(9), 1993, 2540-2546.
- [4] P.A. Nwofe, pH Dependent Optical Properties of Chemically Deposited Sb₂S₃ Thin Films, *Int. J. Nano.Chem.*, 1(3), 2015, 111-116.
- [5] O. E. Ogah, K. R. Reddy, G. Zoppi, I. Forbes, R.W. Miles, Annealing studies and electrical properties of SnS-based solar cells. *Thin Solid Films*, 519(21), 2011, 7425-7428.
- [6] P.E. Agbo, P.A. Nwofe, V. Anigbogu, Synthesis and Characterisation of Nanocrystalline ZnO-Core Shell Thin Films, *J. Chem. Bio. Phy. Sci. Sec. C.*, 5(3), 2015, 2926 – 2929.
- [7] P.A. Nwofe, K.T. Ramakrishna Reddy, J.K. Tan, I. Forbes, R.W. Miles, Thickness Dependent Optical Properties of Thermally Evaporated SnS Thin Films, *Physics Procedia*, 25, 2012, 150 – 157.
- [8] O. E. Ogah, G. Zoppi, I. Forbes, R.W. Miles, Thin films of tin sulphide for use in thin film solar cell devices. *Thin Solid Films*, 517(7), 2009, 2485-2488.
- [9] P.A. Nwofe, K.T. Ramakrishna Reddy, G. Sreedevi, J.K. Tan, I. Forbes, R.W. Miles, Structural, Optical, and Electro-Optical Properties of Thermally Evaporated Tin Sulphide Layers, *Jpn. J. Appl. Phys.*, 51, 2012, 10NC36.
- [10] P.E. Agbo, P.A. Nwofe, Comprehensive Studies on the Optical Properties of ZnO-Core Shell Thin Films, *J. Nano. Adv. Mat.*, 3(2), 2015, 63 – 97
- [11] R. A. Chikwenze, P. A. Nwofe, P. E. Agbo, S. N. Nwankwo, J. E. Ekpe, F. U. Nweke, Effect of Dip Time on the Structural and Optical Properties of Chemically Deposited CdSe Thin Films, *International Journal of Materials Science and Applications*, 4(2), 2015, 101-106
- [12] P.E. Agbo, P.A. Nwofe, Structural and Optical Properties of Sulphurised Ag₂S thin Films, *International Journal of Thin Films Science and Technology*, 4(1), 2015, 9 - 12.
- [13] R. W., Miles, O. E., Ogah, G., Zoppi, I. Forbes, Thermally evaporated thin films of SnS for application in solar cell devices. *Thin Solid Films*, 517(17), 2009, 4702-4705.
- [14] P.A. Nwofe, K.T. Ramakrishna Reddy, R.W. Miles, Influence of Deposition Time on the Properties of Highly-oriented SnS Thin Films Prepared Using the Thermal Evaporation Method, *Advanced Materials Research*, 602-604, 2013, 1409-1412.
- [15] P.E. Agbo, F.U. Nweke, P.A. Nwofe, C.N. Ukwu., Temperature dependent structural and optical properties of doped Cadmium Sulphide thin films, *International Journal of Advanced Research*, 2(10), 2014, 353 – 358.
- [16] J. P. Zimmer, S. W., Kim, S., Ohnishi, E., Tanaka, J. V., Frangioni, M. G. Bawendi, Size series of small indium arsenide-zinc selenide core-shell nanocrystals and their application to in vivo imaging. *Journal of the American Chemical Society*, 128(8), 2006, 2526-2527.
- [17] P.A. Nwofe, Influence of Film Thickness on the Optical Properties of Antimony Sulphide Thin Films Grown by the Solution Growth Technique, *European Journal of Applied Engineering and Scientific Research*, 4(1), 2015, 1 – 6.
- [18] B. Ismail, S. Mushtaq, A. Khan, Enhanced Grain Growth in the Sn Doped Sb₂S₃ thin Film Absorber Materials for Solar Cell Applications, *Chalcogenides Letts.*, 11(1), 2014, 37-45.
- [19] P.A. Nwofe, Prospects and challenges of silver sulphide thin films: A review, *European Journal of Applied Engineering and Scientific Research*, 4(2), 2015, 20-27
- [20] M., Di Giulio, G., Micocci, R., Rella, P., Siciliano, A. Tepore, Optical absorption and photoconductivity in amorphous indium selenide thin films. *Thin Solid Films*, 148(3), 1987, 273-278.
- [21] P.A. Nwofe, K.T. Ramakrishna Reddy, G. Sreedevi, J.K. Tan, I. Forbes, R.W. Miles, Single phase, large grain, p-conductivity-type SnS layers produced using the thermal evaporation method, *Energy Procedia*, 15, 2012, 354-360.
- [22] R. J., Robinson, Z. K. Kun, p-n junction zinc sulfo-selenide and zinc selenide light-emitting diodes, *Applied Physics Letters*, 27(2), 1975, 74-76.
- [23] P.A. Nwofe, K.T. Ramakrishna Reddy, J.K. Tan, I. Forbes, R.W. Miles., On the Structural and Optical Properties of SnS Thin Films Grown by Thermal Evaporation Method, *J. Phys. Conf.: Ser.*, 417, 2013, 012039.
- [24] V. M., Garcia, P. K., Nair, M. T. S. Nair, Copper selenide thin films by chemical bath deposition. *Journal of crystal growth*, 203(1), 1999, 113-124.
- [25] P.A. Nwofe, Deposition and Characterisation of SnS Thin Films for Applications in Photovoltaic Solar Cell Devices. Doctoral thesis, Northumbria University, United Kingdom, 2013.
- [26] Z., Zhang, S., Pang, H., Xu, Z., Yang, X., Zhang, Z., Liu, G. Cui, Electrodeposition of nanostructured cobalt selenide films towards high performance counter electrodes in dye-sensitized solar cells, *RSC Advances*, 3(37), 2013, 16528-16533.
- [27] M. S., Faber, K., Park, M., Cabán-Acevedo, P. K., Santra, S. Jin, Earth-abundant cobalt pyrite (CoS₂) thin film on glass as a robust, high-performance counter electrode for quantum dot-sensitized solar cells. *The Journal of Physical Chemistry Letters*, 4(11), 2013, 1843-1849.
- [28] E., Vayner, R. A., Sidik, A. B., Anderson, B. N. Popov, Experimental and theoretical study of cobalt selenide as a catalyst for O₂ electroreduction. *The Journal of Physical Chemistry C*, 111(28), 2007, 10508-10513.
- [29] J. F., Zhao, J. M., Song, C. C., Liu, B. H., Liu, H. L., Niu, C. J., Mao, Z. P. Zhang, Graphene-like cobalt selenide nanostructures: template-free solvothermal synthesis, characterization and wastewater treatment. *CrystEngComm*, 13(19), 2011, 5681-5684.
- [30] Y., Lai, F., Liu, J., Yang, B., Wang, J., Li, Y. Liu, Photoelectrochemical behavior of electrodeposited CoSe thin films. *Applied Physics Express*, 4(7), 2011, 071201.
- [31] E. S., Smotkin, S., Cervera-March, A. J., Bard, A., Campion, M. A., Fox, T., Mallouk, J. M. White, Bipolar cadmium selenide/cobalt (II) sulfide semiconductor photoelectrode arrays for unassisted photolytic water splitting. *Journal of Physical Chemistry*, 91(1), 1987, 6-8.

- [32] P.A. Nwofe, K.T. Ramakrishna Reddy, J.K. Tan, I. Forbes, M. Leach, D.Y., Jang, R.W. Miles., Investigating the Potential of SnS for Use in Photovoltaic Solar Cell Applications. Proceeding of the Photovoltaic Science, Applications and Technology (PVSAT-8), 2012, pp. 89 -92, Northumbria University, UK, (2nd – 4th April).
- [33] D. E., Speliotis, G., Bate, J. K., Alstad, J. R. Morrison, Hard magnetic films of iron, cobalt, and nickel. *Journal of Applied Physics*, 36(3), 1965, 972-974.
- [34] Z., Yu, J., Du, S., Guo, J., Zhang, Y. Matsumoto, CoS thin films prepared with modified chemical bath deposition. *Thin Solid Films*, 415(1), 2002, 173-176.
- [35] P., Pramanik, S., Bhattacharya, P. K. Basu, A solution growth technique for the deposition of cobalt selenide thin film. *Thin Solid Films*, 149(3), 1987, L81-L84.
- [36] F., Liu, B., Wang, Y., Lai, J., Li, Z., Zhang, Y. Liu, Electrodeposition of cobalt selenide thin films. *Journal of The Electrochemical Society*, 157(10), 2010, D523-D527.
- [37] A. I., Carim, F. H., Saadi, M. P., Soriaga, N. S. Lewis, Electrocatalysis of the hydrogen-evolution reaction by electrodeposited amorphous cobalt selenide films. *Journal of Materials Chemistry A*, 2(34), 2014, 13835-13839.
- [38] B., WANG, F. Y., LIU, J., LI, Y. Q., LAI, Z. A., ZHANG, Y. X. LIU, Preparation and Characterization of Co-Se Thin Films by Electrodeposition. *Journal of Inorganic Materials*, 4, 2011, 011.
- [39] M. L., Gaur, P. P., Hankare, K. M., Garadkar, I. S., Mulla, V. M. Bhuse, Morphological and optoelectronic studies on polycrystalline leaf-like cobalt selenide thin film synthesized using a chemical bath deposition technique. *New Journal of Chemistry*, 38(1), 2014, 255-259.
- [40] Y., Feng, T., He, N. Alonso-Vante, Oxygen reduction reaction on carbon-supported CoSe₂ nanoparticles in an acidic medium. *Electrochimica Acta*, 54(22), 2009, 5252-5256.
- [41] W., Maneepprakorn, M. A., Malik, P. O'Brien, The preparation of cobalt phosphide and cobalt chalcogenide (CoX, X= S, Se) nanoparticles from single source precursors. *Journal of Materials Chemistry*, 20(12), 2010, 2329-2335.
- [42] L.I. Maissel, R. Glang, *Handbook of thin film technology*, McGraw-Hill, New York, 1970.
- [43] P.A. Nwofe, K.T. Ramakrishna Reddy, R.W. Miles, Effects of sulphur and air annealing on the properties of thermally evaporated SnS layers for application in thin film solar cell devices". *Journal of Renewable & Sustainable Energy*, 5, 2013, 011204
- [44] P. A. Nwofe, K. T. Ramakrishna Reddy, J. K. Tan, I. Forbes, M. Leach, D. Y. Jang, and R. W. Miles in: A. Mendez-Vilas (Eds) *Fuelling the Future: Advances in Science and Technologies for Energy Generation, Transmission and Storage*. Boca Raton, Florida: BrownWalker Press, 2012.
- [45] M. Devika, N. K. Reddy, K. Ramesh, R. Ganesan, K. R. Gunasekhar, E. S. R. Gopal, and K. T. Ramakrishna Reddy, "Thickness effect on the physical properties of evaporated SnS films," *Journal of the Electrochemical Society*, vol. 154, pp. H67 – H73, 2007
- [46] P.A. Nwofe, K.T. Ramakrishna Reddy, R.W. Miles. Type Conversion of p-SnS to n-SnS Using a SnCl₄/CH₃OH Heat Treatment, Proceeding of the 39th IEEE Photovoltaic Specialists Conference, Tampa, Florida, USA 14115963, 2013, 2518-2523
- [47] P.A. Nwofe, K.T. Ramakrishna Reddy, R.W. Miles, Determination of the Minority Carrier Diffusion Length of SnS Using Electro-optical Measurements". *Electronic Materials Letters*, 9(3), 2013, 363-366.
- [48] C. Cifuentes, M. Botero, E. Romero, C. Calderón and G. Gordillo, "Optical and structural studies on SnS films grown by co-evaporation," *Braz. J. Phys.*, vol. 36, pp. 1046 - 1049, 2006.